11111 III III III III III III III III I	

Application/Control No.	Applicant(s)/Patent Reexamination	under
10/603,623	KATATA, KEIJI	
Examiner	Art Unit	
Daniel Tekle	2621	

	SEARCHED			
Class	Subclass	Date	Examiner	
386	<b>95</b>	4/2/2007	DT	
386	125-126	4/2/2007	DT	
369	47.14	4/2/2007	рт	
369	53.17	4/2/2007	DT	
		<b>A</b>	•	
	/ 3	100		
/ c	OBJEN 7			
•		_		
			_	

INTERFERENCE SEARCHED			
Subclass	Date	Examiner	
1		j.	
	•		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) and search query attached	4/2/2007	DΤ
combined citation and NPL	4/2/2007	DΤ
Inventor search	4/2/2007	DT
	·	
,	·	